

Applicant: Atsushi Shimoda, et al.

Method and Apparatus for Inspecting Defects...

Atty Docket No. 16869P-031800

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Fig. 1

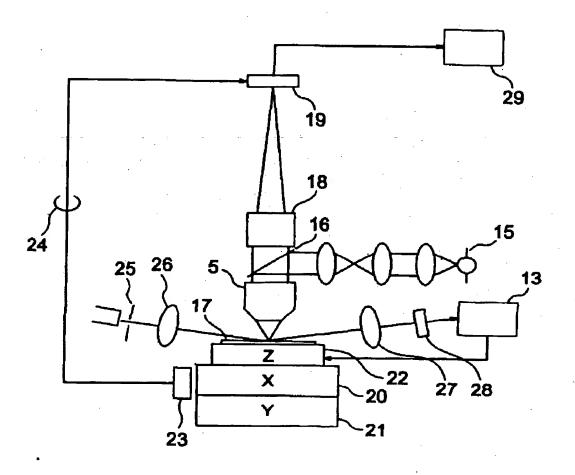
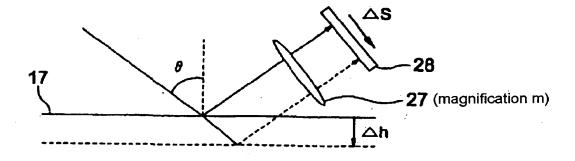


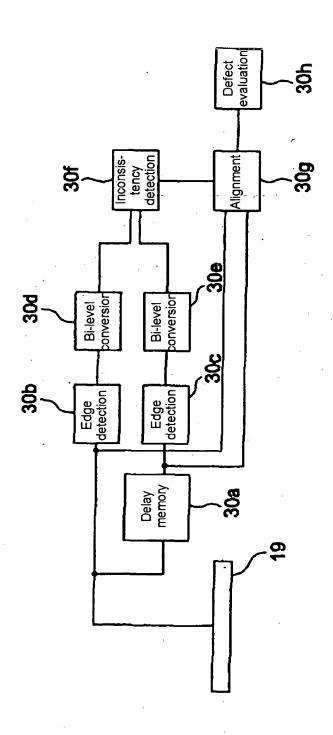
Fig. 2



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Fig. 3



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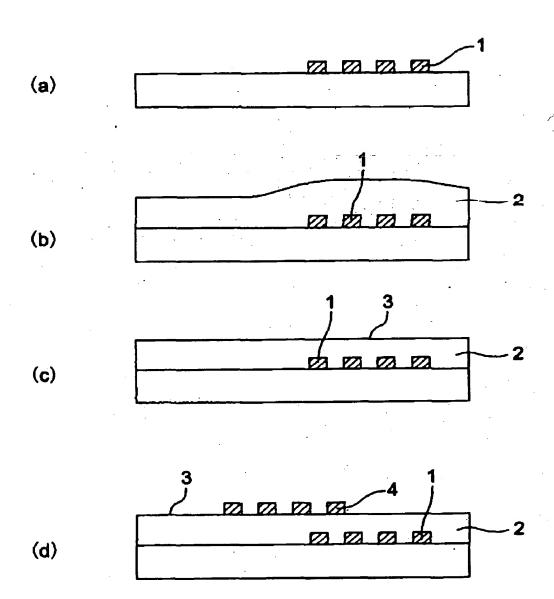
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Fig. 4

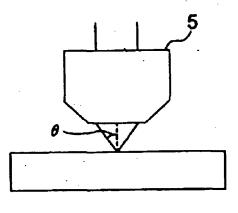


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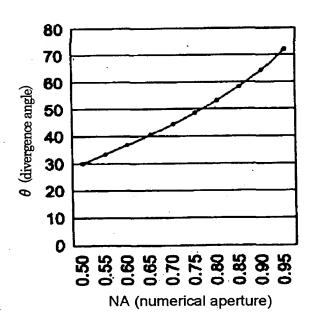
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Fig. 5

(a)



(b)



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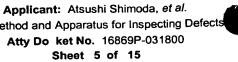
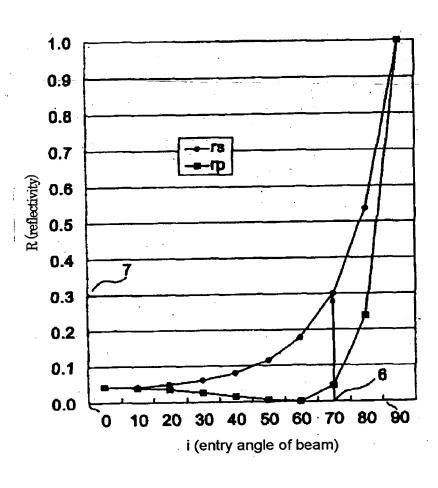


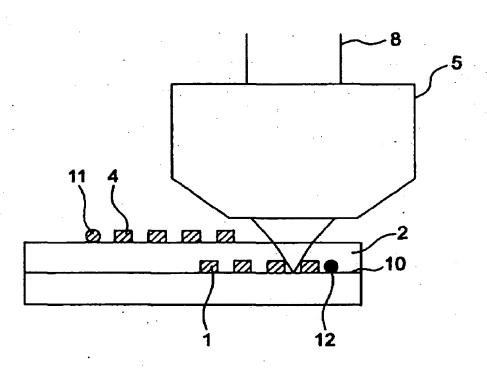
Fig. 6



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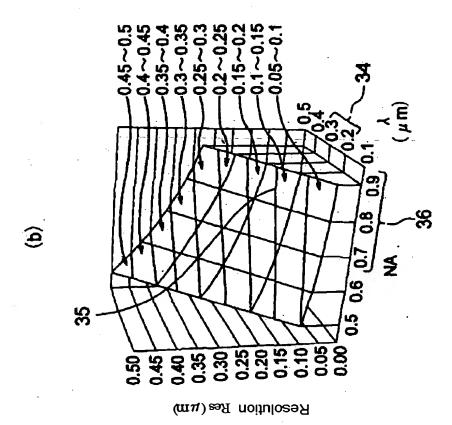
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Fig. 7



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Fig. 8



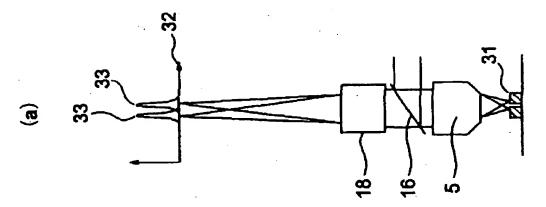
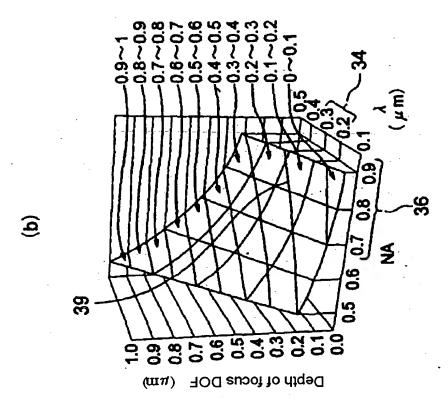
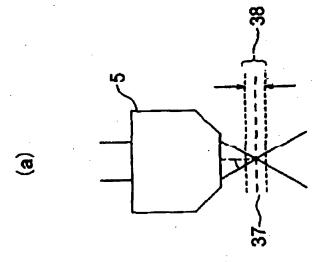


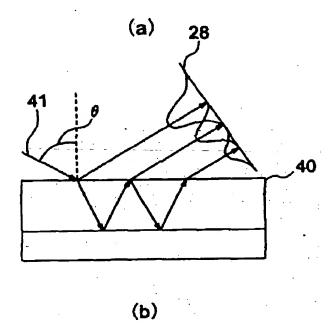
Fig. 9

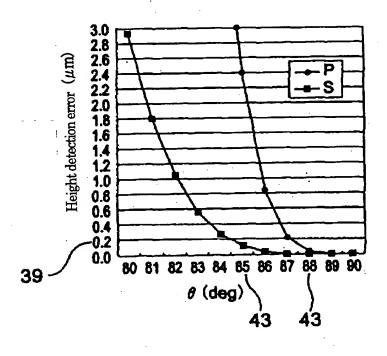




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Fig. 10





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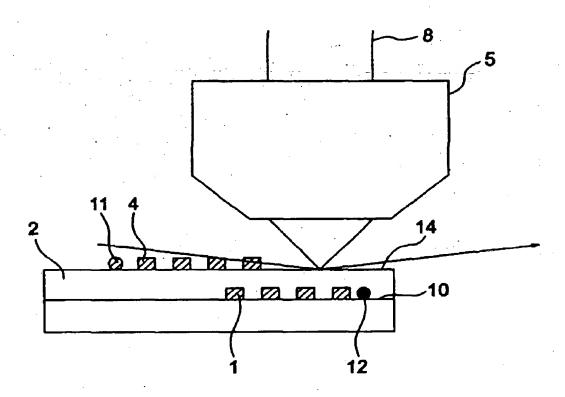
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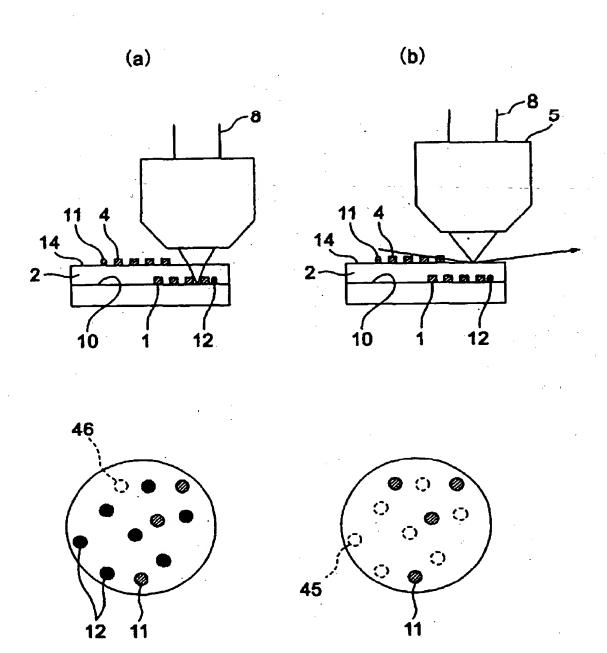
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Fig. 11



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Fig. 12



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Fig. 13

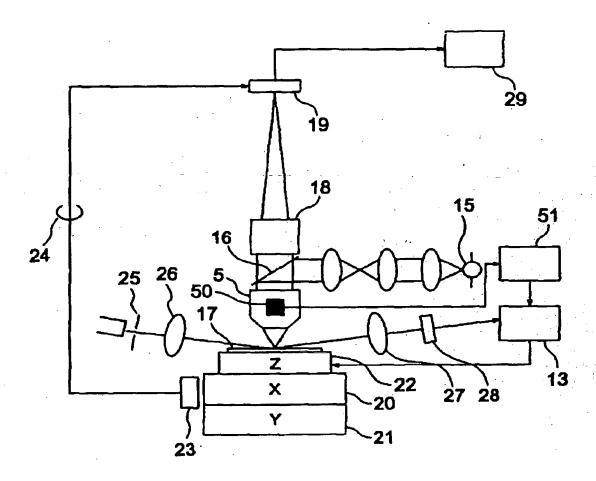
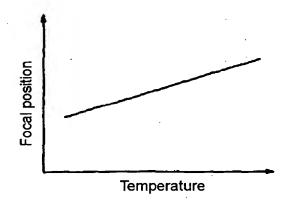
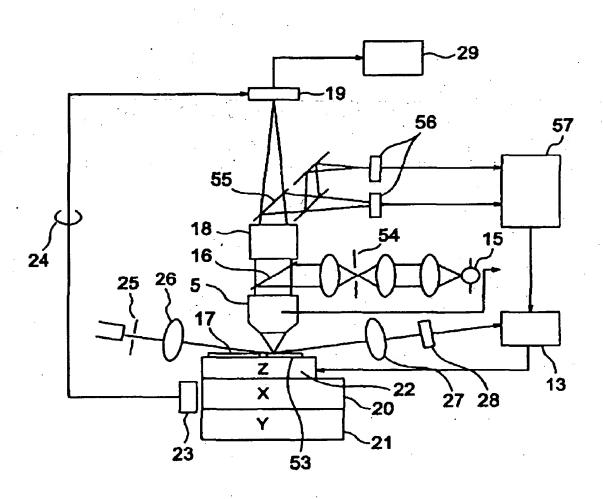


Fig. 14



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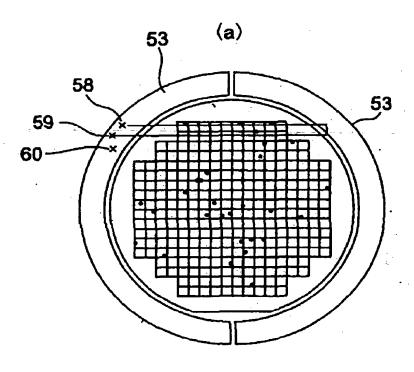
Fig. 15

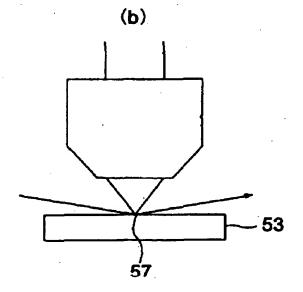


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Fig. 16





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Fig. 17

